

PCN Number:	20210920000.1		PCN Date:	September 20, 2021																			
Title:	Qualification of additional Fab site (UMC-F12) and additional Assembly site (Clark) for select LBC9 devices																						
Customer Contact:	PCN Manager		Dept:	Quality Services																			
Proposed 1st Ship Date:	Dec 18, 2021		Estimated Sample Availability:	Date provided at sample request.																			
Change Type:																							
<input checked="" type="checkbox"/>	Assembly Site	<input type="checkbox"/>	Assembly Process	<input checked="" type="checkbox"/>	Assembly Materials																		
<input type="checkbox"/>	Design	<input type="checkbox"/>	Electrical Specification	<input type="checkbox"/>	Mechanical Specification																		
<input type="checkbox"/>	Test Site	<input type="checkbox"/>	Packing/Shipping/Labeling	<input type="checkbox"/>	Test Process																		
<input type="checkbox"/>	Wafer Bump Site	<input type="checkbox"/>	Wafer Bump Material	<input type="checkbox"/>	Wafer Bump Process																		
<input checked="" type="checkbox"/>	Wafer Fab Site	<input type="checkbox"/>	Wafer Fab Materials	<input type="checkbox"/>	Wafer Fab Process																		
<input type="checkbox"/>	Part number change																						
PCN Details																							
Description of Change:																							
Texas Instruments is pleased to announce the qualification of an additional fab (UMC-F12) and assembly site (Clark) for the selected devices listed in the "Product Affected" section.																							
<table border="1" style="width: 100%; border-collapse: collapse;"> <thead> <tr> <th colspan="3" style="text-align: center;">Current Fab Site</th> <th colspan="3" style="text-align: center;">New Fab Site</th> </tr> <tr> <th style="text-align: center;">Current Fab Site</th> <th style="text-align: center;">Process</th> <th style="text-align: center;">Wafer Diameter</th> <th style="text-align: center;">New Fab Site</th> <th style="text-align: center;">Process</th> <th style="text-align: center;">Wafer Diameter</th> </tr> </thead> <tbody> <tr> <td style="text-align: center;">RFAB</td> <td style="text-align: center;">LBC9</td> <td style="text-align: center;">300 mm</td> <td style="text-align: center;">UMC-F12</td> <td style="text-align: center;">LBC9</td> <td style="text-align: center;">300 mm</td> </tr> </tbody> </table>						Current Fab Site			New Fab Site			Current Fab Site	Process	Wafer Diameter	New Fab Site	Process	Wafer Diameter	RFAB	LBC9	300 mm	UMC-F12	LBC9	300 mm
Current Fab Site			New Fab Site																				
Current Fab Site	Process	Wafer Diameter	New Fab Site	Process	Wafer Diameter																		
RFAB	LBC9	300 mm	UMC-F12	LBC9	300 mm																		
There are no construction differences between the 2 sites																							
Qual details are provided in the Qual Data Section.																							
Reason for Change:																							
Continuity of supply																							
Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / negative):																							
None																							
Impact on Environmental Ratings:																							
Checked boxes indicate the status of environmental ratings following implementation of this change. If below boxes are checked, there are no changes to the associated environmental ratings.																							
RoHS		REACH		Green Status																			
<input checked="" type="checkbox"/> No Change		<input checked="" type="checkbox"/> No Change		<input checked="" type="checkbox"/> No Change																			
<input type="checkbox"/> No Change		<input type="checkbox"/> No Change		<input type="checkbox"/> No Change																			
Changes to product identification resulting from this PCN:																							
Fab Site Information:																							
Chip Site	Chip Site Origin Code (20L)	Chip Site Country Code (21L)	Chip Site City																				
RFAB	RFB	USA	Richardson																				
UMC-F12	F12	TWN	Tainan																				
Assembly Site Information:																							
Assembly Site	Assembly Site Origin (22L)	Assembly Country Code (23L)	Assembly City																				
CDAT	CDA	CHN	Chengdu																				
Clark	QAB	PHL	Angeles City, Pampanga																				
Sample product shipping label (not actual product label)																							



MADE IN: Malaysia
2DC: 2Q:



MSL 2 / 260C/1 YEAR	SEAL DT
MSL 1 / 235C/UNLIM	03/29/04

OPT:
ITEM: 39
LBL: 5A (L)T0:1750

(1P) SN74LS07NSR
(Q) 2000 (D) 0336
(31T) LOT: 3959047MLA
(4W) TKY (1T) 7523483SI2
(P)
(2P) REV: (V) 0033317
(20L) CSO: SHE (21L) CCO: USA
(22L) ASO: MLA (23L) ACO: MYS

Product Affected:

BQ25975YFFR	BQ25975YFFT	BQ25980YFFR	BQ25980YFFT
-------------	-------------	-------------	-------------



TI Information
Selective Disclosure

Qualification Report

Approve Date 13-Sep-2021

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Type	Test Name / Condition	Duration	Qual Device: BQ25980YFF	Qual Device: BQ25975YFF	QBS Product Reference: BQ25980YFFR	QBS Product Reference: BQ25980YFFR	QBS Package Reference: CD3232A0YFFR...	QBS Package Reference: CD3232A1YFFR
-	Bump-Shear	(Per A-T site spec)	-	-	3/150/0	-	1/50/0	-
-	Manufacturability TQ - Testability)	(per mfg. Site specification)	1/Pass	1/Pass	-	-	-	-
-	Pb Surface Mount Solderability	Post 8 Hrs/Steam	-	-	3/66/0	-	-	-
CDM	ESD - CDM	750 V	1/3/0	-	-	-	-	-
CDM	ESD - CDM	1000 V	-	-	-	1/3/0	-	-
CDM	ESD - CDM	1500 V	-	-	1/3/0	-	-	-
HAST	Biased HAST, 130C/85%RH	96 hours	3/231/0	-	3/231/0	-	2/160/0	-
HBM	ESD - HBM	4000 V	1/3/0	-	1/3/0	1/3/0	-	-
HTOL	Life Test, 125C	1000 hours	1/77/0	-	1/77/0	-	1/77/0	2/144/0
HTSL	High Temp Storage Bake 150C	1000 hours	3/231/0	-	-	-	-	-
HTSL	High Temp Storage Bake 170C	420 hours	-	-	3/231/0	-	1/77/0	1/77/0
LU	Latch-up	(Per JESD78, Class I)	1/6/0	-	1/6/0	1/6/0	-	-
LU	Latch-up	(Per JESD78, Class II)	1/6/0	-	1/6/0	1/6/0	-	-
MQ	Manufacturability (Bump)	(per mfg. Site specification)	1/Pass	-	-	-	-	-
PD	Physical Dimensions	(per mechanical drawing)	-	-	3/15/0	-	1/5/0	1/20/0
SBS	Bump-shear	(Per A-T site spec)	-	-	-	-	1/50/0	-
SD	Pb Free Surface Mount Solderability	Post 8 Hrs/Steam	-	-	3/66/0	-	1/22/0	1/22/0

Type	Test Name / Condition	Duration	Qual Device: BQ25980YFF	Qual Device: BQ25975YFF	QBS Product Reference: BQ25980YFFR	QBS Product Reference: BQ25980YFFR	QBS Package Reference: CD3232A0YFFR...	QBS Package Reference: CD3232A1YFFR
TC	Temperature Cycle, -55/125C	700 cycles	3/231/0	-	3/231/0	-	2/160/0	-
UHAST	Unbiased HAST 130C/85%RH	96 hours	3/231/0	-	3/231/0	-	-	-

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
 - The following are equivalent HTOL options based on an activation energy of 0.7eV: 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
 - The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1k Hours, and 170C/420 Hours
 - The following are equivalent Temp Cycle options per JESD47: -55C/125C/700 Cycles and -65C/150C/500 Cycles
 Quality and Environmental data is available at TI's external Web site: <http://www.ti.com/>
Green/Pb-free Status:
 Qualified Pb-Free(SMT) and Green
 - QBS: Qual By Similarity
 - Qual Device BQ25975YFF is qualified at LEVEL1-260C
 - Qual Device BQ25980YFF is qualified at LEVEL1-260C

For questions regarding this notice, e-mails can be sent to the contacts shown below or your local Field Sales Representative.

Location	E-Mail
USA	PCNAmericasContact@list.ti.com
Europe	PCNEuropeContact@list.ti.com
Asia Pacific	PCNAsiaContact@list.ti.com
WW PCN Team	PCN_ww_admin_team@list.ti.com

IMPORTANT NOTICE AND DISCLAIMER

TI PROVIDES TECHNICAL AND RELIABILITY DATA (INCLUDING DATASHEETS), DESIGN RESOURCES (INCLUDING REFERENCE DESIGNS), APPLICATION OR OTHER DESIGN ADVICE, WEB TOOLS, SAFETY INFORMATION, AND OTHER RESOURCES “AS IS” AND WITH ALL FAULTS, AND DISCLAIMS ALL WARRANTIES, EXPRESS AND IMPLIED, INCLUDING WITHOUT LIMITATION ANY IMPLIED WARRANTIES OF MERCHANTABILITY, FITNESS FOR A PARTICULAR PURPOSE OR NON-INFRINGEMENT OF THIRD PARTY INTELLECTUAL PROPERTY RIGHTS.

These resources are intended for skilled developers designing with TI products. You are solely responsible for (1) selecting the appropriate TI products for your application, (2) designing, validating and testing your application, and (3) ensuring your application meets applicable standards, and any other safety, security, or other requirements. These resources are subject to change without notice. TI grants you permission to use these resources only for development of an application that uses the TI products described in the resource. Other reproduction and display of these resources is prohibited. No license is granted to any other TI intellectual property right or to any third party intellectual property right. TI disclaims responsibility for, and you will fully indemnify TI and its representatives against, any claims, damages, costs, losses, and liabilities arising out of your use of these resources.

TI’s products are provided subject to TI’s Terms of Sale (www.ti.com/legal/termsofsale.html) or other applicable terms available either on ti.com or provided in conjunction with such TI products. TI’s provision of these resources does not expand or otherwise alter TI’s applicable warranties or warranty disclaimers for TI products.